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Solved Problems EE 207, Prof. P. R. Nayak, EE, IITB.

Topic: Generation - Recombination

Q1: For a sample with  $R = 10^{-10} \text{ cm}^{-3}$ ;  $N_A = 10^{17} \text{ cm}^{-3}$  estimate the minority carrier lifetime.

Hint  $\frac{dn}{dt} = -k(p - n_i^2)$

$$\frac{d\Delta n}{dt} \approx k N_A \Delta n$$

$$\therefore \frac{1}{\tau} = k N_A$$

Q2: If the above sample is illuminated with  $G = 10^{18} \text{ cm}^{-3} \text{ s}^{-1}$ ; estimate the charge carrier densities.

Hint: Assume low level injection

$$G = R = k N_A \Delta n$$

$$\Rightarrow \Delta n = \frac{G}{k N_A}$$

$$n = n_0 + \Delta n$$

$$\Delta n = \Delta p$$

$$p = p_0 + \Delta p$$

Check whether  $\Delta n < p_0$ . If not analyze in terms of either high level or by retaining all terms.



Q3! For the above sample, estimate the  $G$  <sup>beyond which</sup> ~~for which~~ high level injection condition should be considered? (2)

HINT: When  $\Delta n \approx N_A$ , we need to consider high level injection condition.

$$\Rightarrow \Delta n \approx (k N_A)^{1/2} G \approx N_A$$

$$\Rightarrow G \approx k N_A^{1/2}$$

Q4! For a sample with  $k=20$ ,  $\tau_n = \tau_p$ , estimate the carrier density as a function of  $G$  in  
 (a) low level (b) high level injection condition.

HINT: (a)  $G = R = \frac{\Delta n}{\tau_n}$

$$\Delta n \approx G \tau_n$$

(b)  $G = R = \frac{\Delta n}{(\tau_n + \tau_p)} \Rightarrow \Delta n \approx 2G \tau_n$

Q5! Estimate the trap level at which  $R$  becomes half of that of its theoretical maximum (for intrinsic materials. ( $\tau_p = \tau_n$ ).

HINT: ~~Rmax~~

HINT! For intrinsic material  $R = \frac{n_p - n_i^2}{\tau_p(n + n_i) + \tau_n(p + n_i)}$

the  $R_{max}$  happens at  $n_i = n_i^1$

2)  $R_{max} = \frac{\Delta n}{(\tau_p + \tau_n)}$  | Analysis done in Tutorial 1



$$n_1 = n_i e^{(E_T - E_i)/kT}$$

So, we need to find such that

$$R_{new} = R_{max}/2$$

$$R_{new} = \frac{(np - n_i^2)}{Z_n(p + A) + Z_n(n + n_1)}$$

$$\begin{array}{l} \text{Assuming } E_T > E_i \\ | \quad n_1 > p_1 \end{array}$$

~~with low level injection~~

~~$R_{new}$~~   
For low level injection

$$\begin{array}{l} n = n_i + \Delta n \\ p = n_i + \Delta n \end{array}$$

$$np - n_i^2 = \Delta n(n_i + \Delta n)$$

$$R_{new} \approx \frac{\Delta n \times 2n_i}{Z_n n_i e^{(E_T - E_i)/kT}} = \frac{\Delta n}{4Z_n}$$

$$\Rightarrow \frac{(E_T - E_i)/kT}{e} \approx 8$$

Q6: Find the condition for  $n, p$  at which  $R$  maximizes (assume  $Z_n = Z_p$ ).

Hint: Similar analysis to Q5 will give the answer

Q7: Find the  $n/p$  ratio at  $R$  will be  $1/10^{th}$  of  $R_{max}$ . (assume  $Z_n = Z_p$ ).

Hint: Analysis similar to Q5



(4)

Q8: For a semiconductor with both SRH +  
~~non~~ radiative recombination, find effective  
minority carrier lifetime

HINT: Start with  $\frac{dn}{dt} = k_1(p-n_i^2) + R_{\text{SRH}}$   
and estimate.

Q9: If we remove all electrons and holes  
from an intrinsic semiconductor; estimate the  
time taken to reach equilibrium, (only radiative)

HINT: Solved in tutorials. Seek help from  
your friends who attended tutorial.

Q10: Repeat the above if only SRH recombination  
was present

HINT: Same as above.

Q11: A sample with  $n_i = 10^{10} \text{ cm}^{-3}$ ,  $k_1 = 0$ ,  $\tau_{n2} = \tau_{p2} = 1 \text{ ns}$ .

Draw the E-B diagram

HINT: First estimate,  $n + p$  (decide whether  
low level or high  
level injection)

then use  $(E_{Fn} - E_i) / kT$

$$n = n_i e^{(E_{Fn} - E_i) / kT}$$

$$p = n_i e^{(E_i - E_{Fp}) / kT}$$